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Photo-reduction behavior of sol-gel derived silica materials doped with europium(III) crown ether complex

Ryota Suzuki, Shiori Takei, Eisuke Tashiro, Ken-Ichi Machida*

Center for Advanced Science and Innovation, Osaka University, 2-1 Yamadaoka, Suita, Osaka 565-0871, Japan

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Abstract

Silica-based composite glasses doped with europium(III) crown ether complex, SiO₂:[Eu(15C5)]³⁺, which were prepared by the conventional sol-gel method, showed the red line emissions based on f–f transitions of Eu³⁺ ion and also gave the f–d blue band emission of Eu²⁺ ion at 425 nm after irradiating with UV lights around 320 nm for several minutes even in air. The peak intensity of blue emission band increased with prolonging the duration of irradiation, and furthermore such enhancement in intensity still continued even after stopping the UV light irradiation. The 15-crown-5 ether ligands and silanol groups (–Si–OH) in the silica-based matrices played special roles for stabilizing the Eu²⁺ ion generated by the photo-reduction and the subsequent reduction of Eu³⁺ ion without any light irradiation. © 2005 Elsevier B.V. All rights reserved.

Keywords: Europium complex; Organic-inorganic composites; Divalent europium; 15-Crown-5 ether; Photo-reduction

1. Introduction

Recently, the sol-gel method has been attracting attentions as the typical way to prepare functional materials, e.g. optical glasses, dielectric ceramics and so on, at the lower temperature than the conventional solid state reactions [1–5]. In addition, it is easy to produce the functional materials is the ease of fabrication to produce the materials with complicated shapes by it, owing to the fluidity of gel solutions under the mild processing conditions, such as low temperature and atmospheric pressure.

Many organic–inorganic composites have been prepared by using such sol–gel method, since such composite materials can incorporate the organic components without any decomposition of them. Moreover, the composition of organic and inorganic compounds can be controlled to optimize their physical properties such as optical and electrical ones. Therefore, the sol–gel method has a great potential for creating new functional materials. The sol–gel derived silica-based glasses doped with some europium(III) or terbium(III) complexes show the strong red or green line emissions and good stability at the temperature around 473–573 K [6–10]. Furthermore, the excellent persistent spectral hole burning (PSHB) properties have been observed on the SiO₂:[Eu(15C5)]³⁺ composite glasses [11]. The fast formation of hole has been ascribed to the rapid photo-reduction from Eu³⁺ to Eu²⁺ ion and the hole is stable even at room temperature [12].

In this study, the SiO₂: $[Eu(15C5)]^{3+}$ composite glasses were prepared by the sol-gel method and the photoreduction behaviors were studied on the basis of their photoluminescence, ESR and FT-IR measurements. In addition, their good PSHB properties were elucidated by discussing the mechanisms for the photo-reduction of Eu³⁺ ion.

2. Experimental

2.1. $SiO_2:[Eu(15C5)]^{3+}$ composites

The organic–inorganic composite glasses of SiO_2 :[Eu (15C5)]³⁺ were prepared by following procedures: the solution containing tetramethoxysilane (TMOS), deionized

^{*} Corresponding author. Tel.: +81 66 879 4209; fax: +81 66 879 4209. *E-mail address:* machida@casi.osaka-u.ac.jp (K.-I. Machida).

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water, ethanol, anhydrous europium(III) chloride and 15crown-5 ether with a molar ratio of 1:5:10:0.03:0.09 was stirred vigorously to obtain the transparent and homogeneous sol solution. A few drops of diluted HCl solution as a catalyst were added to the above sol solution, and then the solution was cast to a polystyrene cup and dried at 323 K for 1 week. In order that the gelation takes place completely, furthermore, the resultant gels were kept at 363 K for 1 week additionally.

The surface modification was made for a part of SiO₂: $[Eu(15C5)]^{3+}$ composite glasses. The SiO₂: $[Eu(15C5)]^{3+}$ gel solids were ground to the powders by an agate mortar and exposed to the vapor of 1,1,1,3,3,3-hexamethyldisilazane ((CH₃)₃SiNHSi(CH₃)₃) at 363 K for 12 h in each sealed reac-

tor tube. The reaction was performed as follows:

$$2(-Si-OH) (glass surface) + (CH_3)_3 SiNHSi(CH_3)_3$$

$$\rightarrow 2(-Si-O-Si(CH_3)_3) (glass surface) + NH_3.$$

2.2. PMMA: [Eu(15C5)]³⁺ composite

An appropriate amount of polymethylmethacrylate (PMMA: n = 1000) (10 g) was dissolved into 70 g of acetone, and then a part of the solution (23.5 g) was mixed with anhydrous europium chloride (0.0930 g), 15-crown-5 ether (0.237 g) and dimethylformamide (2.00 g) and stirred vig-



Fig. 1. Photo-luminescence spectra of the $SiO_2:[Eu(15C5)]^{3+}$ composite glass monoliths before and after UV light (320 nm) irradiation for (a) emission and (b) excitation spectra of Eu^{2+} ion, and (c) emission and (d) excitation spectra of Eu^{3+} ion.

orously. The resulting transparent solution was cast into a cuvette and dried at 323 K for 1 week in air, followed by drying additionally at 363 K for 1 week.

2.3. Characterization of the composite materials

Fluorescence spectra of the SiO₂: $[Eu(15C5)]^{3+}$ composite monoliths or glass powder were measured on a fluorescence spectrophotometer (Hitachi F-4500) equipped with a xenon lump as the light source. Electron spin resonance (ESR) spectra were measured by using an electron spinning resonance spectrometer (BRUKER ESP-300) at room temperature, and MgO:Mn²⁺ was used as an internal standard material to evaluate the *g* values of specimens. The IR spectra were recorded on a FT-IR-430 spectrometer (JASCO) using the KBr method in a range of 400–4000 cm⁻¹.

3. Results and discussion

Fig. 1 shows the photo-luminescence spectra measured before and after the UV light ($\lambda = 320$ nm) irradiation for the monolith samples of SiO_2 : $[Eu(15C5)]^{3+}$. Before the irradiation, the spectra were composed of the several peaks corresponding to the f-f transition of Eu³⁺ ion. For the irradiated samples, however, the blue band emission characteristic of Eu²⁺ ion was observed and the peak intensity increased with prolonging the irradiation time. Consequently, the red line emissions were inversely weakened. In addition, this reduction reaction from Eu³⁺ to Eu²⁺ ion was still continued even for 24 h after stopping the UV light irradiation. This continuous reduction suggests that some defects such as oxygen-associated hole center (Si-O⁻-Si) [13] are generated in silica-based matrices during the UV light irradiation, and the successive photo-reduction of Eu³⁺ ion is caused by an electron transfer from such defects as a negative charge. However, the existences of hole centers and increases or decreases of them were confirmed in detail.

The ESR spectrum of SiO₂: $[Eu(15C5)]^{3+}$ after the UV light irradiation for 1 h is shown in Fig. 2. The *g* value of spectrum was in good concordance with the previous work (*g* = 2.0057) [14]. This shows the existence of Eu²⁺ ion in the silica-based composite matrices.

Fig. 3(A) shows time dependences of the emission peak (425 nm) intensity based on Eu^{2+} ion for the SiO₂:[Eu(15C5)]³⁺, PMMA:[Eu(15C5)]³⁺ and SiO₂:Eu³⁺ (free from 15-crown-5 ether ligand) composite materials. All the materials were excited by the UV light at 320 nm. The blue band emission derived from Eu^{2+} ion was observed on the SiO₂:[Eu(15C5)]³⁺ composite, but not obviously detected on the other PMMA:[Eu(15C5)]³⁺ and SiO₂:Eu³⁺ composite materials.

Concentration dependences of the blue emission peak intensities (excited at 320 nm) for the $SiO_2:[Eu(15C5)]^{3+}$ composite monolith containing the various amounts of 15-crown-5 ether ligand are shown in Fig. 3(B) and the com-



Fig. 2. An ESR spectrum of SiO_2 :[Eu(15C5)]³⁺ sample after the UV light irradiation.



Fig. 3. Dependences of (A) time and (B) concentration dependence (15-crown-5 ether) on the emission peak (425 nm) intensity for the $SiO_2:[Eu(15C5)]^{3+}$, PMMA: $[Eu(15C5)]^{3+}$ and $SiO_2:Eu^{3+}$ glass monoliths under the excitation at 320 nm.

positions of starting materials and solvents employed are summarized in Table 1. The transparent composite solids were obtained from the gel solutions of $SiO_2:[Eu(15C5)]^{3+}$ with the four composition ratios of (a–d). The blue emission peak intensity of Eu²⁺ ion was enhanced with increasing the

Table 1 Starting materials and solvents for SiO₂:[Eu(15C5)]³⁺ composite glasses (molar ratio)

	TMOS	H_2O	EtOH	EuCl ₃	15C5	Sample condition
(a)	1	5	10	0.03	0.03	Transparent
(b)	1	5	10	0.03	0.09	Transparent
(c)	1	5	10	0.03	0.15	Transparent
(d)	1	5	10	0.03	0.21	Transparent
(e)	1	5	10	0.03	0.30	Opaque



Fig. 4. FT-IR spectra of the SiO_2 :[Eu(15C5)]³⁺ composite glass powders before and after the surface modification.

molar ratio of 15-crown-5 ether to Eu^{2+} ion. The opaque and inhomogeneous specimen, however, finally formed from the gel solution with the composition (e). These results indicate that the silica-based glass network and the 15-crown-5 ether ligand strongly affect to the photo-reduction behavior of Eu^{2+} ion of the SiO₂:[Eu(15C5)]³⁺ composite glasses. Also, the Eu³⁺ ions re-oxidized from the Eu²⁺ ions were always observed on a series of our experiments.

A FT-IR spectrum of the SiO₂: $[Eu(15C5)]^{3+}$ composite glass powder modified by 1,1,1,3,3,3-hexamethyldisilazane is shown in Fig. 4, together with that of the untreated SiO₂: $[Eu(15C5)]^{3+}$ composite one. The absorption peak derived from O–H stretching mode at around 3300 cm⁻¹ was decreased by the surface modification with $-Si(CH_3)_3$ group, suggesting that the H atom of -OH group in SiO₂ matrix was adequately changed to $-Si(CH_3)_3$.

Fig. 5 shows time dependences observed on the untreated and surface-treated SiO₂:[Eu(15C5)]³⁺ composite glass powders by successively monitoring the emission intensity at 425 nm under the excitation at 320 nm. Compare to the untreated SiO₂:[Eu(15C5)]³⁺ composite, the photo-reduction from Eu³⁺ to Eu²⁺ ion was suppressed for the surfacemodified SiO₂:[Eu(15C5)]³⁺ composite glass. The photoreduction caused by residual silanol groups, however, was observed on the surface-modified sample. This means that the silanol group is one of the important factors for the photoreduction of Eu³⁺ ion induced by the UV light irradiation.

A series of experimental results allow us to propose the photo-reduction mechanism of Eu^{3+} ions of the SiO₂:[Eu(15C5)]³⁺ composite materials as follows: at first, the electron in the ground state of Eu^{3+} ion is excited to the charge transfer band by UV light irradiation [15]. This excited Eu^{3+} ion receives one electron of the unshared electron pairs from the O atom of neighboring silanol group, so that the reduction from Eu^{3+} to Eu^{2+} ion takes place. The



Fig. 5. A time dependence of the emission peak (425 nm) intensity for the SiO₂: $[Eu(15C5)]^{3+}$ composite glass powders before and after the surface modification under the excitation at 320 nm.

15-crown-5 ether ligand contributes to stabilize the resultant Eu^{2+} ion by forming the $Eu(15C5)^{2+}$ complex, of which the oxidation potential has found to shift to the positive side compared to the free Eu^{2+} ion [16,17]. The values of redox potential for the free $Eu^{3+/2+}$ and complexed $Eu(15C5)^{3+/2+}$ ion pairs are -150 and -60 mV (versus SCE), respectively [17]. This is due to the good size fitting effect to accommodate such large Eu^{2+} ion in the center cavity of 15-crown-5 ether ligand. Meanwhile, the silanol group generates the radical cation such as $[-Si-OH]^{\bullet+}$, and Eu^{3+} ion is reduced by combining with the neighboring radical cations to form the -Si-O-Si- network. The following equation is the proposed whole reaction:

$$2[Eu(15C5)]^{3+} + 2[-Si-OH]^{\bullet+} (radical cation)$$

$$\rightarrow 2[Eu(15C5)]^{2+} + -Si-O-Si-2H^{+} + \frac{1}{2}O_{2}$$

The chain reaction-like reduction mechanism of Eu^{3+} ion after stopping the UV light irradiation for the SiO₂:[Eu(15C5)]³⁺ composite is ascribed to migrate the negative charge from the defect, viz. so-called oxygen-associated hole center (Si–O⁻–Si) [13].

4. Conclusions

The silica-based organic–inorganic composite glasses of $SiO_2:[Eu(15C5)]^{3+}$ easily generate and stabilize the photoreduced Eu^{2+} ion under the irradiation of UV lights. The ESR measurements directly demonstrate the formation of Eu^{2+} ion in the $SiO_2:[Eu(15C5)]^{3+}$ composite glasses. In addition, such photo-reduction still proceeds successively after stopping the UV light radiation for the monolith samples of $SiO_2:[Eu(15C5)]^{3+}$. The mechanisms for such photoreduction of Eu³⁺ ion are certainly elucidated by the electron donation of silanol group and stabilization of crown ether ligand. The Eu³⁺ ion is reduced by receiving an electron from the O atom with unshared electron pairs of silanol group, and furthermore the resultant Eu²⁺ ion is stabilized by the complexation with 15-crown-5 ether ligand under the UV irradiation. Moreover, the oxygen associated hole center (Si–O⁻–Si) formed under the UV light irradiation slowly release the electron, by which Eu³⁺ ion is still reduced without any UV light.

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